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INSULATED GATE BIPOLAR TRANSISTOR

Features

- UltraFastTM: Optimized for minimum saturation voltage and operating frequencies up to 40 kHz in hard switching, > 200 kHz in resonant mode
- Very low conduction and switching losses
- Fully isolated package (2,500 Volt AC/RMS)
- Very low internal inductance (≤ 5 nH typ.)
- Industry standard outline



- Designed for increased operating efficiency in power conversion: PFC, UPS, SMPS, Welding, Induction heating
- Lower overall losses available at frequencies ≥ 20kHz
- · Easy to assemble and parallel
- Direct mounting to heatsink
- Lower EMI, requires less snubbing
- Plug-in compatible with other SOT-227 packages



$$V_{CES} = 600V$$

 $V_{CE(on) typ.} = 1.49V$

GA100NA60U

Ultra-Fast[™] Speed IGBT



Absolute Maximum Ratings

	Parameter	Max.	Units
V _{CES}	Collector-to-Emitter Breakdown Voltage	600	V
I _C @ T _C = 25°C	Continuous Collector Current	100	
I _C @ T _C = 100°C	Continuous Collector Current	50	A [
I _{CM}	Pulsed Collector Current	200	
I _{LM}	Clamped Inductive Load Current@	200]
V _{GE}	Gate-to-Emitter Voltage	± 20	V
V _{ISOL}	RMS Isolation Voltage, Any Terminal to Case, t=1 min	2500	
P _D @ T _C = 25°C	Maximum Power Dissipation	250	۱۸/
P _D @ T _C = 100°C	Maximum Power Dissipation	100	
TJ	Operating Junction	-55 to + 150	
T _{STG}	Storage Temperature Range	-55 to + 150	°C
	Mounting Torque, 6-32 or M3 Screw	12 lbf •in(1.3N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
R _{θJC}	Junction-to-Case, IGBT		0.50	00/14/
R _{θJC}	Thermal Resistance, Junction-to-Case, Diode		1.0	C/W
R _{0CS}	Case-to-Sink, Flat, Greased Surface	0.05		
Wt	Weight of Module	30		gm
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Electrical Characteristics @ $T_J = 25^{\circ}C$ (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions	
V _{(BR)CES}	Collector-to-Emitter Breakdown Voltage3	600	—	—	V	$V_{GE} = 0V, I_C = 250\mu A$	
$\Delta V_{(BR)CES} / \Delta T_J$	Temperature Coeff. of Breakdown Voltage	—	0.36	—	V/°C	$V_{GE} = 0V, I_C = 1.0mA$	
V _{CE(on)}	Collector-to-Emitter Saturation Voltage	—	1.49	2.1		I _C = 50A	$V_{GE} = 15V$
		—	1.80	-	V	I _C = 100A	See Fig. 1, 4
		—	1.47	—		$I_C = 50A, T_J = 150^{\circ}C$	
V _{GE(th)}	Gate Threshold Voltage	3.0	—	6.0		$V_{CE} = V_{GE}, I_C = 250 \mu A$	
$\Delta V_{GE(th)}/\Delta T_J$	Temperature Coeff. of Threshold Voltage	—	-7.6	—	mV/°C	$V_{CE} = V_{GE}, I_C = 250 \mu A$	
g fe	Forward Transconductance ④	34	52	—	S	$V_{CE} = 100V, I_{C} = 50A$	
I _{CES}	Zero Gate Voltage Collector Current		—	250	μA	$V_{GE} = 0V, V_{CE} = 600V$	
		—	—	1.3	mA	$V_{GE} = 0V, V_{CE} = 600V,$	$T_J = 150^{\circ}C$
V _{FM}	Diode Forward Voltage Drop	—	1.3	1.6	V	I _C = 50A	See Fig. 12
			1.16	1.3		$I_{C} = 50A, T_{J} = 150^{\circ}C$	
I _{GES}	Gate-to-Emitter Leakage Current	_	_	±100	nA	$V_{GE} = \pm 20V$	

Switching Characteristics @ $T_J = 25^{\circ}C$ (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions			
Qg	Total Gate Charge (turn-on)	_	430	640		I _C = 50A			
Qge	Gate - Emitter Charge (turn-on)	_	48	72	nC	$V_{CC} = 400 V$	See	Fig. 7	
Q _{gc}	Gate - Collector Charge (turn-on)	_	130	190		$V_{GE} = 15V$			
t _{d(on)}	Turn-On Delay Time		57			$T_J = 25^{\circ}C$			
t _r	Rise Time		80		ns	$I_{\rm C} = 60$ A, $V_{\rm CC} = 480$ V			
t _{d(off)}	Turn-Off Delay Time		240	—		$V_{GE} = 15V, R_{G} = 5.0\Omega$			
t _f	Fall Time		120	_		Energy losses include "tail" and			
Eon	Turn-On Switching Loss		0.41			diode revers	diode reverse recovery.		
E _{off}	Turn-Off Switching Loss		2.51		mJ				
Ets	Total Switching Loss		2.92	4.4					
t _{d(on)}	Turn-On Delay Time		57			T _J = 150°C,			
tr	Rise Time		80		ns	$I_{C} = 60A, V_{CC} = 480V$			
t _{d(off)}	Turn-Off Delay Time		380			$V_{GE} = 15V, R_{G} = 5.0\Omega$			
t _f	Fall Time		170			Energy losses include "tail" and			
E _{ts}	Total Switching Loss		4.78		mJ	diode reverse recovery.			
LE	Internal Emitter Inductance	_	2.0	—	nH				
Cies	Input Capacitance	_	7400	_		$V_{GE} = 0V$			
Coes	Output Capacitance	_	730	—	pF	$V_{CC} = 30V$	S	See Fig. 6	
C _{res}	Reverse Transfer Capacitance	_	90	_	1	f = 1.0 MHz			
t _{rr}	Diode Reverse Recovery Time	_	90	140	ns	$T_J = 25^{\circ}C$	See Fig.		
		_	120	180		T _J = 125°C	13	I _F = 50A	
Irr	Diode Peak Reverse Recovery Current	_	7.3	11	Α	$T_J = 25^{\circ}C$	See Fig.		
			11	16		T _J = 125°C	14	$V_{R} = 200V$	
Q _{rr}	Diode Reverse Recovery Charge	_	360	550	nC	T _J = 25°C	See Fig.		
		_	780	1200		T _J = 125°C	15	di/dt = 200Aµs	
di _{(rec)M} /dt	Diode Peak Rate of Fall of Recovery	_	370	—	A/µs	$T_J = 25^{\circ}C$	See Fig.		
	During t _b		220	—		T _J = 125°C	16		

Details of note ① through ④ are on the page 7

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Fig. 1 - Typical Output Characteristics



Fig. 2 - Typical Transfer Characteristics







Fig. 4 - Typical Collector-to-Emitter Voltage vs. Junction Temperature

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Fig. 5 - Maximum Effective Transient Thermal Impedance, Junction-to-Case





Fig. 7 - Typical Gate Charge vs. Gate-to-Emitter Voltage

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Collector-to-Emitter Current www.irf.com

Fig. 10 - Typical Switching Losses vs.

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Fig. 12 - Typical Forward Voltage Drop vs. Instantaneous Forward Current



Fig. 13 - Typical Reverse Recovery vs. di_f/dt 6



Fig. 14 - Typical Recovery Current vs. di_f/dt www.irf.com

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Fig. 15 - Typical Stored Charge vs. di_f/dt Fig. 16 - Typical di_{(rec)M}/dt vs. di_f/dt

Notes:

- 0 Repetitive rating: V_{GE}=20V; pulse width limited by maximum junction temperature (figure 20)
- $V_{CC} = 80\% (V_{CES}), V_{GE} = 20V, L = 10\mu H, R_G = 5.0\Omega$ (figure 19)
- ③ Pulse width \leq 80µs; duty factor \leq 0.1%.
- ④ Pulse width 5.0µs, single shot.

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Fig. 17a - Test Circuit for Measurement of I_{LM} , E_{on} , $E_{off(diode)}$, t_{rr} , Q_{rr} , I_{rr} , $t_{d(on)}$, t_r , $t_{d(off)}$, t_f



Fig. 17b - Test Waveforms for Circuit of Fig. 17a, Defining $E_{off},\,t_{d(off)},\,t_{f}$







Fig. 17d - Test Waveforms for Circuit of Fig. 17a, Defining E_{rec}, t_{rr}, Q_{rr}, I_{rr}

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Figure 17e. Macro Waveforms for Figure 17a's Test Circuit



Figure 18. Clamped Inductive Load Test Circuit

Figure 19. Pulsed Collector Current Test Circuit

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SOT-227 Package Details

Dimensions are shown in millimeters (inches)



Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.

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